

N-Channel MOSFET

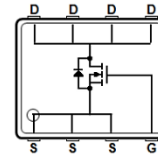
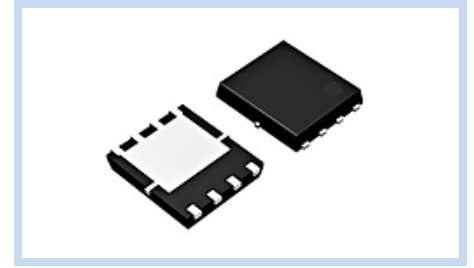
100V 34A 33W DFN3x3-8L

MFT10N34D33

MERITEK

FEATURE

- $R_{DS(ON)} < 16m\Omega$ at $V_{GS}=10V$
- $R_{DS(ON)} < 22m\Omega$ at $V_{GS}=4.5V$
- High Density Cell Design for Ultra Low Rdson
- Application: DC/DC Converter, Consumer Electronic Power Supply, Synchronous Rectification, Motor control, Invertors



MECHANICAL DATA

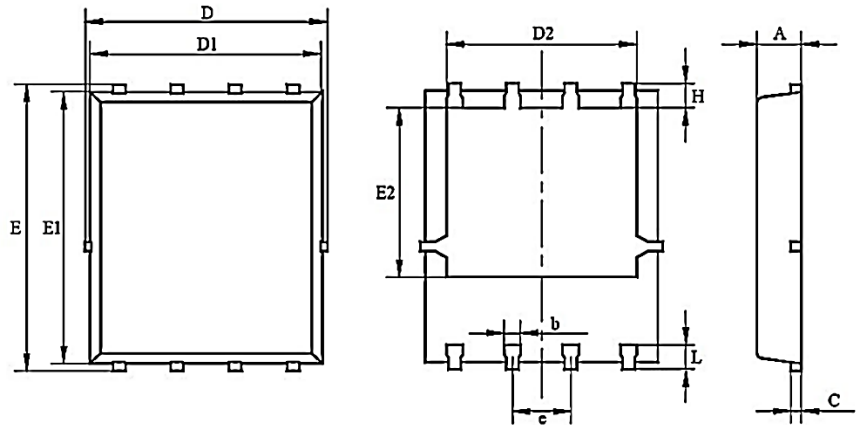
- Case: DFN3x3-8L, Molded Plastic
- Terminal: Solderable per MIL-STD-750, Method 2026

MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current – Continuous	I_D	$T_c=25^\circ C$	34
		$T_c=100^\circ C$	24
Drain Current – Pulsed	I_{DM}	140	A
Power Dissipation	P_D	33	W
Single Pulse Avalanche Current	I_{AS}	14.7	A
Single Pulse Avalanche Energy	E_{AS}	54	mJ
Typical Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	62.5	$^\circ C/W$
Typical Thermal Resistance, Junction to Case	$R_{\theta JC}$	4.5	$^\circ C/W$
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55~175	$^\circ C$

DIMENSIONS

Item	Min (mm)	Max (mm)
A	0.70	0.90
b	0.24	0.35
c	0.21	0.25
D	3.10	3.30
D1	2.90	3.10
D2	2.40	2.60
e	0.60	0.70
E	3.10	3.30
E1	2.90	3.10
E2	1.65	1.85
H	0.33	0.53
L	0.30	0.50



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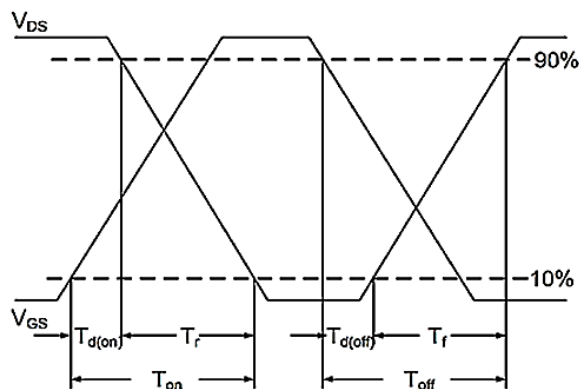
ELECTRICAL CHARACTERISTICS

Off Characteristics	Conditions	Symbol	Min	Typ.	Max	Unit
Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	BV_{DSS}	100	--	--	V
Zero Gate Voltage Drain Current	$V_{DS}=100V, V_{GS}=0V$	I_{DSS}	--	--	1	μA
Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	I_{GSS}	--	--	± 100	nA
On Characteristics	Conditions	Symbol	Min	Typ.	Max	Unit
Static Drain-Source On-Resistance	$V_{GS}=10V, I_D=15A$	$R_{DS(ON)}$	--	12.0	16.0	m Ω
	$V_{GS}=4.5V, I_D=10A$		--	15.5	22.0	
Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	$V_{GS(th)}$	1.2	-	2.5	V
Forward Transconductance	$V_{DS}=5V, I_D=10A$	g_{FS}	-	20	-	S
Dynamic Characteristics	Conditions	Symbol	Min	Typ.	Max	Unit
Total Gate Charge	$V_{DS}=50V, I_D=15A, V_{GS}=4.5V$	Q_g	--	10	--	nC
			--	20	--	
Gate-Source Charge	$V_{DS}=50V, I_D=15A, V_{GS}=10V$	Q_{gs}	--	4.2	--	nC
Gate-Drain Charge		Q_{gd}	--	3.8	--	
Turn-On Delay Time	$V_{DS}=50V, I_D=15A, V_{GS}=10V, R_G=4.7\Omega$	$T_{d(on)}$	--	12	--	ns
Rise Time		T_r	--	15	--	
Turn-Off Delay Time		$T_{d(off)}$	--	11	--	
Fall Time		T_f	--	3.5	--	
Input Capacitance	$V_{DS}=50V, V_{GS}=0V, f=1MHz$	C_{iss}	--	1123	--	pF
Output Capacitance		C_{oss}	--	424	--	
Reverse Transfer Capacitance		C_{rss}	--	15	--	
Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1MHz$	R_g	--	1	--	Ω
Drain-Source Body Diode	Conditions	Symbol	Min	Typ.	Max	Unit
Continuous Source Current	-	I_S	--	--	34	A
Pulse Source Current	-	I_{SM}	--	--	140	A
Diode Forward Voltage	$V_{GS}=0V, I_S=1A$	V_{SD}	--	--	1.2	V
Reverse Recovery Time	$I_S=15A, di/dt=100A/\mu s$	T_{rr}	--	38	--	ns
Reverse Recovery Charge		Q_{rr}	--	41	--	nC

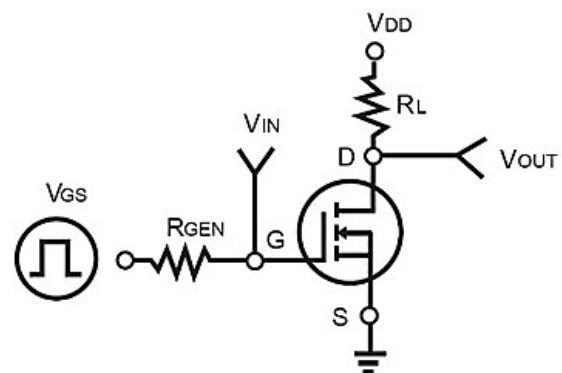
Note:

- $T_A=25^\circ C$ unless otherwise noted
- The data tested by pulsed, pulse width $\leq 100\mu s$, duty cycle $\leq 2\%$, Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}=175^\circ C$.
- Limited by $T_{J(MAX)}$, starting $T_J=25^\circ C, L=0.5mH, R_g=25\Omega, I_{AS}=14.7A, V_{GS}=10V$
- Device mounted on FR-4 substrate PC board, 2oz copper, with 1-inch² copper plate in still air.

Switching Time Waveform

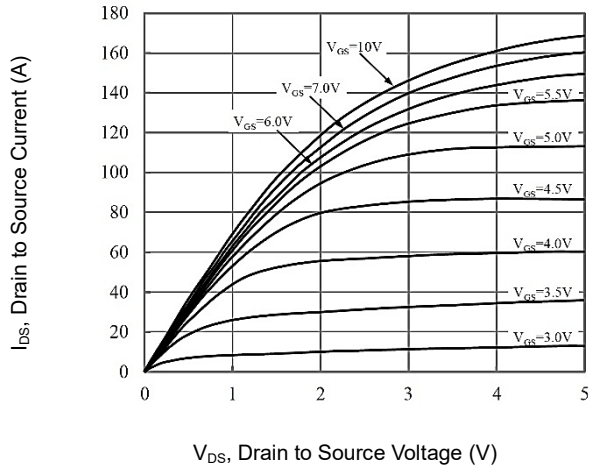


Switching Test Circuit

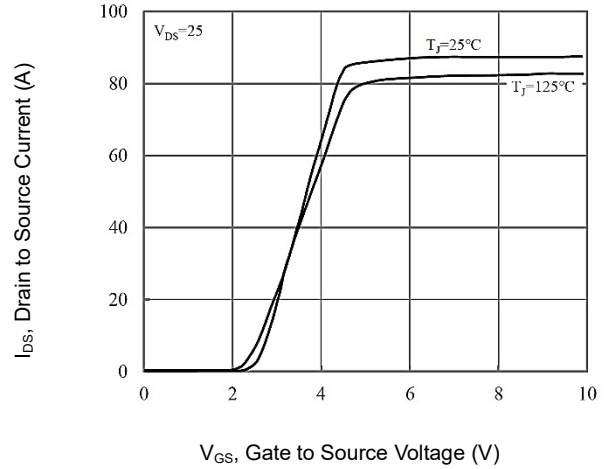


CHARACTERISTIC CURVES

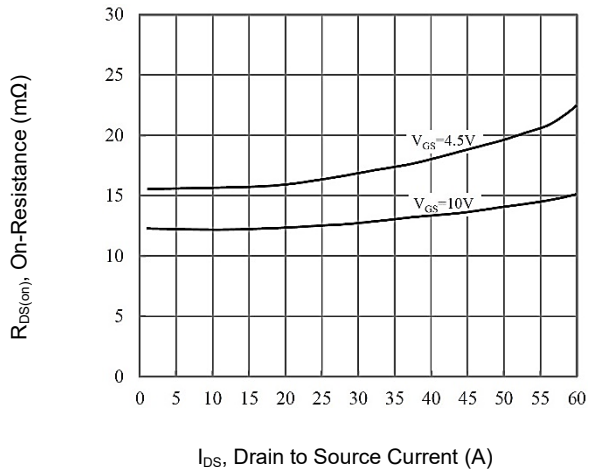
On-Region Characteristic



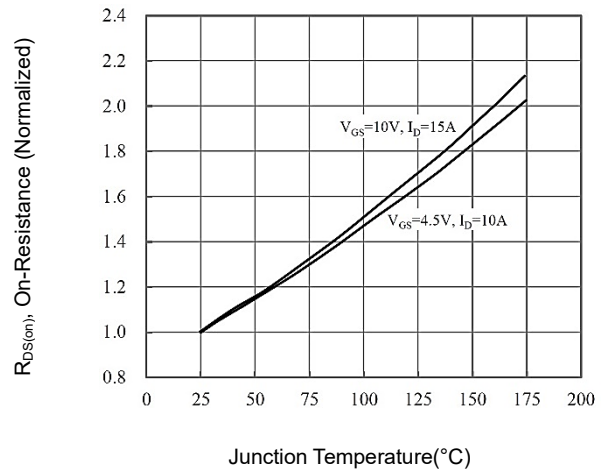
Transfer Characteristics



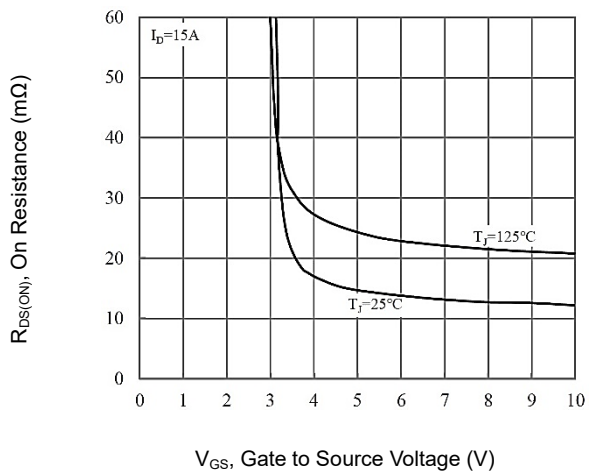
On-Resistance vs. Drain Current



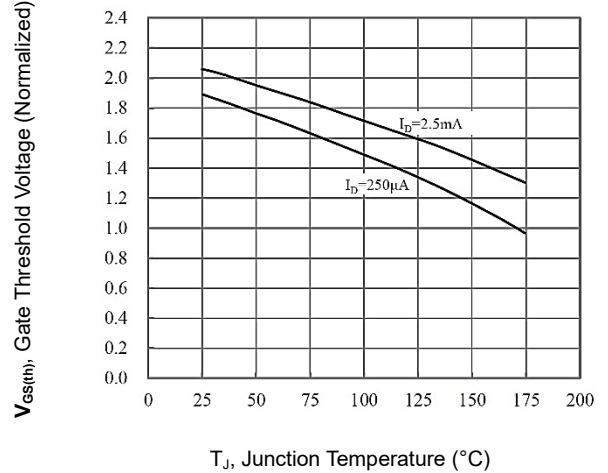
On-Resistance vs. Junction Temperature



On-Resistance Variation with Vgs

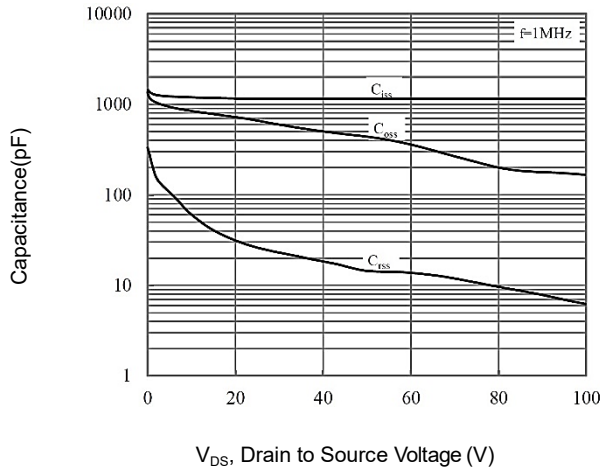


Gate Threshold Voltage vs. Temperature

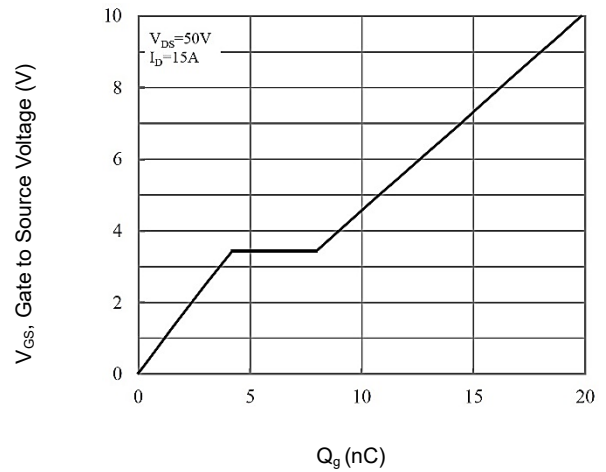


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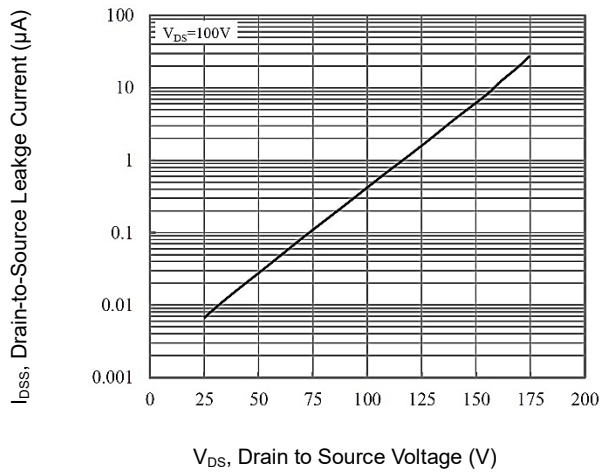
Capacitance vs. Drain-Source Voltage



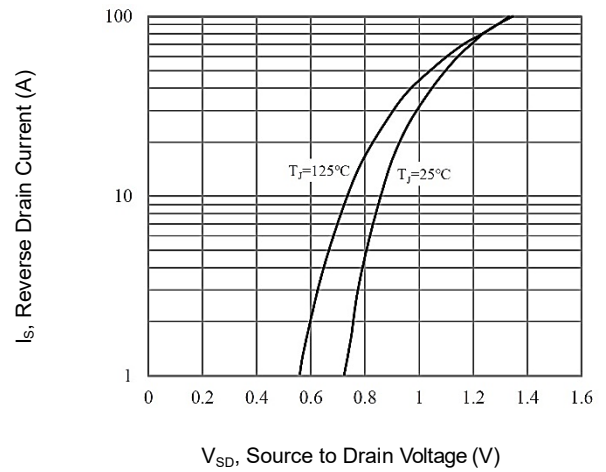
Gate-Charge Characteristics



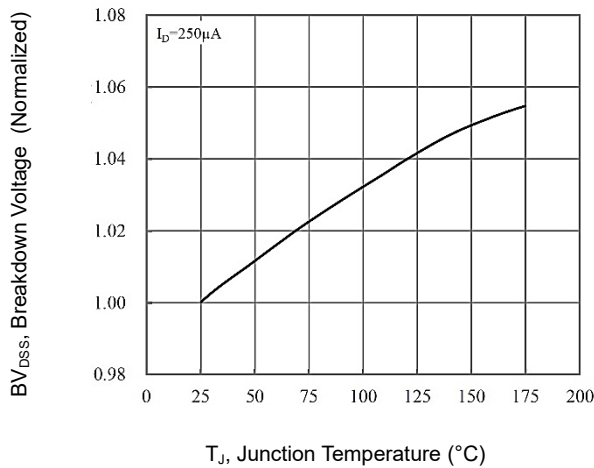
Drain-Source Leakage Current vs. Temperature



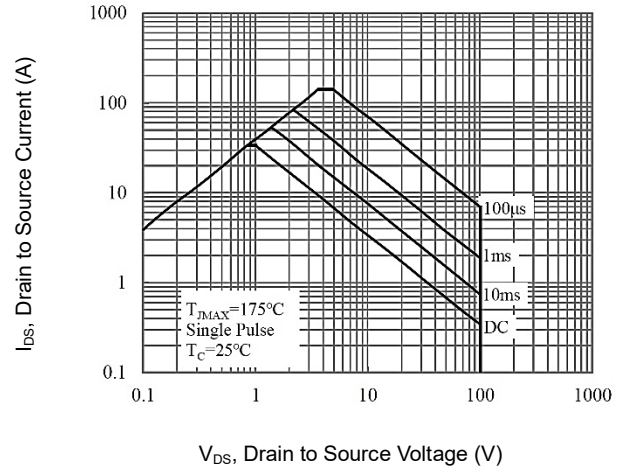
Reverse Diode Forward Voltage



Breakdown Voltage vs Temperature

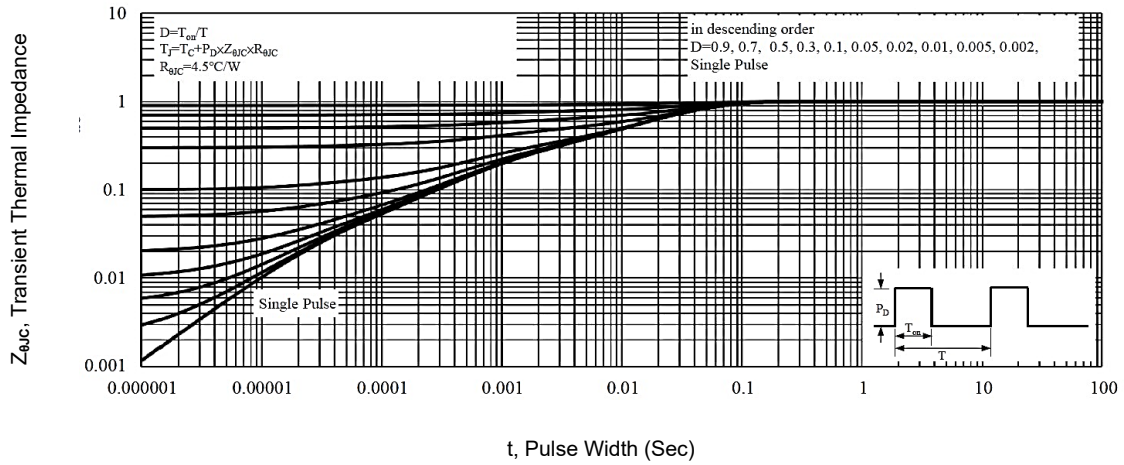


Maximum Safe Operating Area



CHARACTERISTIC CURVES

Normalized Transient Thermal Impedance from Junction to Case



Normalized Transient Thermal Impedance from Junction to Ambient

